



UNITED STATES PATENT AND TRADEMARK OFFICE

UNITED STATES DEPARTMENT OF COMMERCE
 United States Patent and Trademark Office
 Address: COMMISSIONER FOR PATENTS
 P.O. Box 1450
 Alexandria, Virginia 22313-1450
 www.uspto.gov

BIBDATASHEET

CONFIRMATION NO. 1112

Bib Data Sheet

SERIAL NUMBER 10/621,445	FILING DATE 07/18/2003 RULE	CLASS 324	GROUP ART UNIT 2829	ATTORNEY DOCKET NO. 030868
-----------------------------	---------------------------------------	--------------	------------------------	----------------------------------

APPLICANTS

Yasuo Yamagishi, Kawasaki, JAPAN;

Takeshi Shioga, Kawasaki, JAPAN;

John David Baniecki, Kawasaki, JAPAN; Kazuaki Kurihara, Kawasaki, JAPAN;

** CONTINUING DATA *****

** FOREIGN APPLICATIONS *****

JAPAN 2002-214476 07/23/2002

JAPAN 2003-020663 01/29/2003

JAPAN 2003-270360 07/02/2003

verified
John H.

IF REQUIRED, FOREIGN FILING LICENSE GRANTED

** 08/12/2004

Foreign Priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no	STATE OR	SHEETS	TOTAL	INDEPENDENT
35 USC 119 (a-d) conditions met <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after	COUNTRY	DRAWING	CLAIMS	CLAIMS
Verified and Acknowledged <i>John H.</i> Examiner's Signature Initials	JAPAN	15	31	8

ADDRESS

23850

ARMSTRONG, KRATZ, QUINTOS, HANSON & BROOKS, LLP

1725 K STREET, NW

SUITE 1000

WASHINGTON, DC

20006

TITLE

Probe card and testing method of semiconductor chip, capacitor and manufacturing method thereof

FILING FEES	FEES: Authority has been given in Paper	<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees (Filing) <input type="checkbox"/> 1.17 Fees (Processing Ext. of
-------------	---	---

RECEIVED 1368	No. _____ to charge/credit DEPOSIT ACCOUNT		time)
	No. _____ for following:		
	<input type="checkbox"/> 1.18 Fees (Issue)		
	<input type="checkbox"/> Other _____		
		<input type="checkbox"/> Credit	